	DESCRIPTION C	JF REVI	SIONS	BY	CHKD	DAT	E	COU	NT DE	ESCRIPTI	ON OF RE\	/ISIONS	BY	CHK	D D/	ATE
1	BLE STANDAI	RD									ſ					
	OPERATING TEMPERATURE RAN	-55° TO +85° (pote1) STO								DRAGE −10℃ TO +6						
RATING VOLTAGE		30 V AC/E				AC/DC	API			PLICABLE		BM23F	R0.6-	40DS	-0.35	V(**)
		0.3A							CONNE	DNNECTOR BM23FR0.6-40DS-0.35V						
	CONTREME								NS							
	SPECIFICATION TEST METHOD									REQUIRE	EMENT	S		QT	AT	
CONSTRUCTION		<b>_</b>														1
GENERAL EXAMINATION		CONFIRMED VISUALLY AND BY MEASURING INSTRUMENT.								CORDING	TO DRAWI	NG.			x	x
MARKING		CONFIRMED VISUALLY.													x	X
ELECTRICAL CHARAC															-	
GONTACT RESISTANCE		20mV AC OR LESS 1kHz, 1mA								0mΩ MA)	x				x	_
		100V DC								MQ MIN					x	_
		100V AC FOR 1min.									VER OR BRE	AKDOW	'N		X	1 -
<i>n</i> =	ICAL CHARA	CTERI	STICS	5								-				
愛座 RATION		10 TIMES INSERTIONS AND EXTRACTIONS.							-		FRESISTAN					
info										OF PATRS.					X	-
בי לב אופיראדוסא														1.00		
fu la	FREQUENCY 10 TO 55 TO 10 Hz, APPROX 5min SINGLE AMPLITUDE 0.75mm, 10CYCLES,								<ol> <li>NO ELECTRICAL DISCONTINUITY OF 1µs.</li> <li>NO DAMAGE, CRACK OR LOOSENESS</li> </ol>					x	_	
		FOR 3 DIRECTIONS.								OF PARTS.						
ntati <del>tit</del> NOCE	490 m/s <sup>2</sup> DURATION OF PULSE 11ms AT 3 TIMES FOR 3 DIRECTIONS.							-	<ol> <li>NO ELECTRICAL DISCONTINUITY OF 1µs.</li> <li>NO DAMAGE, CRACK OR LOOSENESS</li> </ol>					x	_	
									OF PARTS.							
	IMENTAL CHA				N 105 °C							0	000			T
୩ନେହାଁD CHANGE OF ଅନ୍ୟୋମନେସ୍ୟାର		TEMPERATURE $-55 \rightarrow +85^{\circ}$ TIME $30 \rightarrow 30 \text{ min}$							-	① CONTACT RESISTANCE: 100mΩ MAX ② INSULATION RESISTANCE: 50MΩ MIN						
nan		UNDER 5 CYCLES. (RELOCATION TIME TO CHAMBER: WITHIN2~3 MIN)							0 1	③ NO DAMAGE, CRACK OR LOOSENESS					X	-
DAMP HEAT		EXPOSED AT 40±2°C, 90 TO 95%, 96h.							, c	OF PARTS. ① CONTACT RESISTANCE: 100mΩ MAX						
CSTEADY STATE)									-	② INSULATION RESISTANCE: 25MΩ MIN					x	_
pplicati										③ NO DAMAGE, CRACK OR LOOSENESS OF PARTS.						
SUTPHUR DIOXIDE		EXPOSED IN 25 PPM FOR 96h, 25℃, 75±5%RH.								① CONTACT RESISTANCE: 100mΩ MAX						
lease lease	(Test standard : JIS C 60068)													X	-	
in case mat me please																
=																
	-	~ -	~ ~			~ ~		_	]							
	RAWING	j H	ÜΗ	RF	·FF	Кŀ	NCI	-								
	This is subj							_								
			ona	ge i					J							
											CHECKE			- <u>-</u>		
REMARKS Note 1; INCI		RATURE RISING BY CURRENT.					DRAW									
			S.H.JUNG					NG	ъ.н	JUNG	H.W.JC	,   '.	o.ran	<sup>ч</sup>   (	17.05	-
Unless otherwise specified, refer to JIS C 5402 and IEC 60512 17.05.08								08	17.	05.08	17.05.0	8 1	7.05.0	8	DEF	ア
	QUALIFICATION					TEST	X: APP	LICAE	BLE TE							
	HIROSE KOREA CO.,LTD. SPECIF						ICATION SHEET			BM23FR0.6-40DP-0.35V(89						
	SE KOREA CO	D.,LTE	).		SPEC	CIFIC	ATION	SHE	ΕI	R	M23FR	) 6-40	-9ח	0.35		25)
		-		NG NO.			AHON		EI ENO.	В	M23FRC	).6-40	)DP-	0.35	V(89	95) 1 /